RPI-132US

Appln. No.: 10/828,654

Amendment Dated November 9, 2005 Reply to Office Action of August 9, 2005

<u>Amendments to the Claims:</u> This listing of claims will replace all prior versions, and listings, of claims in the application

Listing of Claims:

1. (Currently Amended) An apparatus for the generation of high-energy terahertz radiation comprising:

a source effective to produce optical radiation; and

a semiconductor substrate having a refractive index, n, and <u>an integral grating</u> structure formed on a surface of the semiconductor substrate in which a photo-generated dipole <u>is generated upon interaction</u> with the optical radiation, the photo-generated dipole oriented <u>by the grating structure</u> to radiate terahertz radiation having power at least about n² times higher than the power of the terahertz radiation radiated by a photo-generated dipole which is not so oriented.

- 2. (Original) The apparatus of claim 1 wherein the source is a laser that produces pulsed optical radiation having a femtosecond duration.
- 3. (Original) The apparatus of claim 2 wherein the laser produces pulsed optical radiation having a wavelength of about 800 nm.
- 4. (Original) The apparatus of claim 3 wherein the laser is a titanium:sapphire laser.
- 5. (Original) The apparatus of claim 1 wherein the photo-generated dipole is oriented substantially perpendicular to the propagating direction of the terahertz radiation.
- 6. (Currently Amended) The apparatus of claim 1 wherein the semiconductor substrate has a grating with structure has an apex angle of about ninety degrees.
- 7. (Currently Amended) The apparatus of claim $6-\underline{1}$ wherein the size of the grating structure is up to about 5 μ m.
- 8. (Currently Amended) The apparatus of claim 6-1 wherein the semiconductor substrate is GaAs.

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9. (Currently Amended) The apparatus of claim 6-1 wherein the optical radiation of the laser is incident substantially perpendicular to the grating of the semiconductor substrate.

10. (Currently Amended) <u>An apparatus for the generation of high-energy</u> terahertz radiation comprising:

a source effective to produce optical radiation; and

a semiconductor substrate having a refractive index, n, and a photo-generated dipole generated upon interaction with the optical radiation, the photo-generated dipole oriented to radiate terahertz radiation having power at least about n² times higher than the power of the terahertz radiation radiated by a photo-generated dipole which is not so oriented; and

The apparatus of claim 1 further comprising a structure of a polytetrafluoroethylene base with an InAs film forming a grating on the surface of the semiconductor substrate.

- 11. (Original) The apparatus of claim 10 wherein the grating has an apex angle of about ninety degrees.
- 12. (Original) The apparatus of claim 10 wherein the InAs film has a thickness greater than the absorbance length of the optical radiation.
- 13. (Original) The apparatus of claim 10 wherein the optical radiation is incident substantially perpendicular to the grating of the semiconductor substrate.
- 14. (Currently Amended) The apparatus of claim 1 wherein the semiconductor substrate has grating structure includes a grating formed by a series of structures each having the configuration of a right-triangle.
- 15. (Original) The apparatus of claim 14 wherein the optical radiation is incident on the surface of the semiconductor substrate at the Brewster's angle to each individual structure of the grating.

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16. (Currently Amended) A method for the generation of high-energy terahertz radiation comprising:

providing a semiconductor substrate having a refractive index, n, and a modified surface an integral grating structure;

applying an electric field to the semiconductor substrate; and

directing optical radiation to the semiconductor substrate, thereby creating a photo-generated dipole emitting terahertz radiation,

the photo-generated dipole oriented by the <u>grating structure modified surface</u> of the semiconductor substrate to emit terahertz radiation having power at least about n² times higher than the power of the terahertz radiation radiated by a photo-generated dipole which is not so oriented.

- 17. (Original) The method of claim 16 wherein the photo-generated dipole is oriented substantially perpendicular to the propagating direction of the terahertz radiation.
- 18. (Currently Amended) The method of claim 16 wherein the semiconductor substrate is GaAs, the surface of the semiconductor substrate is modified by a grating with structure has an apex angle of about ninety degrees, and the optical radiation is incident substantially perpendicular to the grating structure of the semiconductor substrate.
- 19. (Currently Amended) The method of claim 16 wherein the <u>grating</u> structure includes surface of the semiconductor substrate is modified by a polytetrafluoroethylene base with an InAs film forming a grating on the surface of the semiconductor substrate, the InAs film has a thickness greater than the absorbance length of the optical radiation, and the optical radiation is incident substantially perpendicular to the grating of the semiconductor substrate.
- 20. (Currently Amended) The method of claim 16 wherein the <u>grating</u> <u>structure includes</u> <u>surface of the semiconductor substrate is modified by</u> a grating formed by a series of structures each having the configuration of a right triangle and the optical radiation is incident on the surface of the semiconductor substrate at the Brewster's angle to each individual structure of the grating.